

Application/Control No.	Applicant(s)/Patent under Reexamination
10/771,590	CHEN ET AL.
Examiner	Art Unit
DAVID Y. ENG	2155

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	JEAR	СПЕВ	,
Class	Subclass	Date	Examiner
709	213 223 236	7/29/2007	DE
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
709	213			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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